

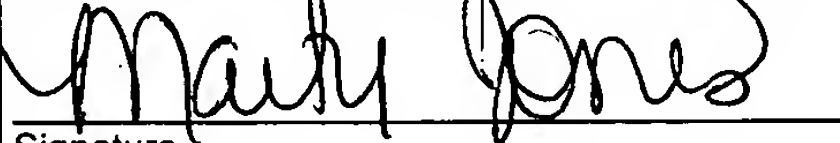


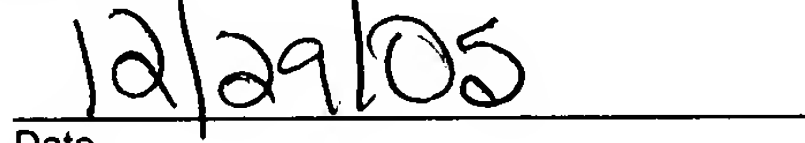
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: DALE HARRISON  
Filed: SEPTEMBER 23, 2003  
For: SEMICONDUCTOR PROCESSING TECHNIQUES UTILIZING  
VACUUM ULTRAVIOLET REFLECTOMETER  
Serial No.: 10/669,030  
Group Art Unit: 2878  
Examiner: HANNAHER, C.  
Atty Dckt. METR:002

NUMBER: EV559591315US

I hereby certify that this paper or fee is being deposited with the United States Postal Service "EXPRESS MAIL POST OFFICE TO ADDRESSEE" service, postage prepaid, under 37 CFR 1.10 on the date indicated above and is address to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

  
Signature

  
Date

**FOURTH SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the documents listed on attached Form PTO-1449 be considered by the Examiner and made of record.

In accordance with 37 C.F.R §§ 1.97(g) and (h), this Supplemental Information Disclosure Statement is not to be construed as a representation that a search has been made, and is not to be construed to be an admission that (a) the information cited is, or is considered to be,

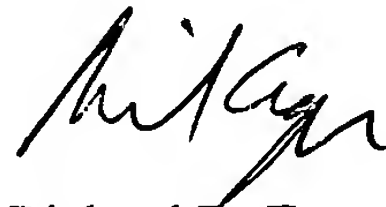
material to patentability as defined in 37 C.F.R. § 1.56(b); and/or (b) that the information cited is, or is considered to be prior art.

Pursuant to §1.97(c), this Supplemental Information Disclosure Statement is being submitted after the period specified in §1.97(b), but prior to the mailing of a final action under §1.113, a notice of allowance under §1.311, or an action that otherwise closes prosecution of the application, and pursuant to 37 C.F.R. § 1.97(c)(2), the fee set forth in §1.17(p) (\$180) is enclosed.

If an appropriate check has not been enclosed, or if it is insufficient, the Commissioner is hereby authorized to deduct said fee from Deposit Account No. 10-1205.

Applicant respectfully requests that the listed documents be made of record in the present case.

Respectfully submitted,



Richard D. Egan  
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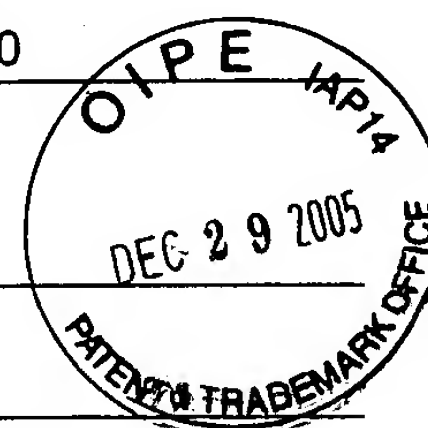
Enclosures

**Form PTO-1449** (modified)

List of Patents and Publications for Applicant's

**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

Atty. Docket No.  
METR:002Serial No.  
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Dale A. HarrisonFiling Date:  
September 23, 2003Group:  
2878U.S. Patent Documents  
See Page 1Foreign Patent Documents  
N/AOther Art  
See Page 1**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A31	US2002/0030826 A1	3/14/02	Chalmers et al.			7/3/01
	A32	4,368,983	1/18/83	Bennett			11/13/80

**Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

**Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
	C11	Rubloff, "Surface Reflectance Spectroscopy System", Technical Disclosure, Ip.com, <a href="http://www.ip.com">www.ip.com</a> , May 1, 1977, 5 pgs.

**Examiner:****Date Considered:**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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*Marty Jones*  
Signature

12/29/05  
Date

**THIRD SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97, and 1.98, it is respectfully requested that this Supplemental Information Disclosure Statement be entered and the document(s) listed on attached Form PTO-1449 be considered by the Examiner and made of record.

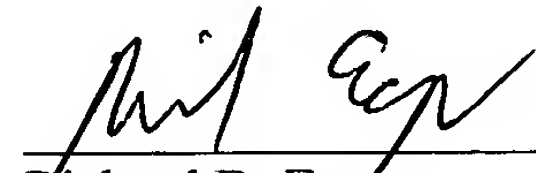
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considered to be prior art.

The references C1-C9 which we listed on the attached PTO-1449 have been previously submitted in an IDS. This Supplemental Information and Disclosure Statement provides a more full citation of each reference on the PTO-1449 form.

Applicant respectfully requests that the listed document(s) be made of record in the present case.

Respectfully submitted,



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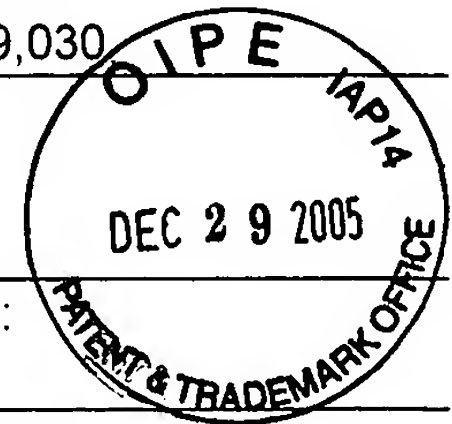
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See PageForeign Patent Documents  
See PageOther Art  
See Pages 1-2**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	A1						

**Foreign Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						

**Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)**

Exam. Init.	Ref. Des.	Citation
	C1	McPherson Product Brochure "Reflectometer for Sample Analysis," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
	C1A	McPherson Product Brochure "Spectral Reflectometer," McPherson, Inc., Massachusetts, November 12, 2001, 1 pg.
	C2	McPherson Product Brochure "VUVaS Spectrophotometers for 115 nm to >380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-4 pps.
	C3	McPherson Product Brochure "VUVaS Spectrophotometers, Made to Measure 115-380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-8 pps.
	C4	Acton Research Product Brochure "Acton Research Purged CAMS Optical Measurement System," Acton Research Corporation, Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
	C5	"The Thin Film tool for next generation lithography at 157nm," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet On February 19, 2002, 1pg.
	C6	"SE and GXR combined on the same instrument," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet on February 19, 2002, 1pg.
	C7	"The ideal Thin Film characterization unit for Development and Pilot Line environment," Web page from <a href="http://www.sopra-sa.com">http://www.sopra-sa.com</a> , Sopra, Printed From Internet on February 19, 2002, 1 pg.

**Examiner:****Date Considered:**

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Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
	C8	"VUV-VASE <sup>TM</sup> , The Award Winning VUV-VASE <sup>TM</sup> is the latest addition to our line of Spectroscopic Ellipsometers," Web pages from <a href="http://www.jawoolam.com">http://www.jawoolam.com</a> , J.A. Woollam Company, Nebraska, Printed From Internet on November 5, 2002, 1-2 pps.
	C9	"Vacuum UV Spectroscopic Ellipsometers," Web pages from <a href="http://www.sentech.de">http://www.sentech.de</a> , Sentech Instruments, Printed From Internet on February 20, 2002, 1-3 pps.

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